

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 10/622,933 Confirmation No: 3481
Applicant : Chee Hong Liao
Filed : July 18, 2003
Title : Method of Processing Test Patterns for an Integrated Circuit
Art Unit : 2128
Examiner : Saif A. Alhija
Docket No. : M&N-IT-465
Customer No. : 24131

Hon. Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

A M E N D M E N T UNDER 37 CFR § 1.116

Sir:

Responsive to the final Office action dated April 10, 2007 kindly amend the above-identified application as follows:

- **Amendments to the Claims** are reflected in the listing of claims which begins on page 2 of this paper.
- **Remarks** begin on page 9 of this paper.